

Deutsche Akkreditierungsstelle GmbH

Annex to the Accreditation Certificate D-K-17602-01-00 according to DIN EN ISO/IEC 17025:2005

Valid from: 20.01.2020

Date of issue: 20.01.2020

Holder of certificate:

Tektronix GmbH
Heinrich-Pesch-Straße 9-11, 50739 Köln

Head: Dipl.-Ing. Ralf Riedel

Deputy head: Luca Johnen

Accredited as calibration laboratory since: 10.07.1995

Calibration in the fields:

Electrical quantities

DC and low frequency quantities

- DC voltage
- DC current
- DC resistance

High frequency quantities

- Oscilloscope quantities *)
- Risetime *)
- Bandwidth *)

Time and frequency quantities

- Frequency *)

*) Also on site calibration

Abbreviations used: see last page

*The certificate together with its annex reflects the status at the time of the date of issue. The current status of the scope of accreditation can be found in the database of accredited bodies of Deutsche Akkreditierungsstelle GmbH.
<https://www.dakks.de/en/content/accredited-bodies-dakks>*

Annex to the accreditation certificate D-K-17602-01-00

Permanent Laboratory

Calibration and Measurement Capabilities (CMC)

Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹⁾	Remarks
DC voltage measurement instruments	10 mV to 220 mV		$4 \cdot 10^{-6} \cdot U + 2 \mu\text{V}$ $5 \cdot 10^{-6} \cdot U + 3 \mu\text{V}$ $5 \cdot 10^{-6} \cdot U + 10 \mu\text{V}$ $5 \cdot 10^{-6} \cdot U + 0.15 \text{ mV}$ $6 \cdot 10^{-6} \cdot U + 1 \text{ mV}$	U = measured value
	> 220 mV to 2.2 V			
sources	> 2.2 V to 22 V		$5 \cdot 10^{-6} \cdot U + 3 \mu\text{V}$ $4 \cdot 10^{-6} \cdot U + 9 \mu\text{V}$ $5 \cdot 10^{-6} \cdot U + 15 \mu\text{V}$ $5 \cdot 10^{-6} \cdot U + 0,15 \text{ mV}$ $7 \cdot 10^{-6} \cdot U + 1,5 \text{ mV}$	
	> 22 V to 220 V			
sources	> 220 V to 1100 V			
	10 mV to 100 mV			
DC current measurement instruments	> 0.1 V to 1 V		$45 \cdot 10^{-6} \cdot I + 7 \text{ nA}$ $43 \cdot 10^{-6} \cdot I + 70 \text{ nA}$ $50 \cdot 10^{-6} \cdot I + 0.40 \mu\text{A}$ $65 \cdot 10^{-6} \cdot I + 0.50 \mu\text{A}$ $0.2 \cdot 10^{-3} \cdot I + 4 \mu\text{A}$ $0.21 \cdot 10^{-3} \cdot I + 0.14 \text{ mA}$	I = measured value
	> 1 V to 10 V			
current probes	> 10 V to 100 V		$0.22 \cdot 10^{-3} \cdot I + 0.35 \mu\text{A}$ $0.5 \cdot 10^{-3} \cdot I + 4 \mu\text{A}$ $0.22 \cdot 10^{-3} \cdot I + 0.35 \mu\text{A}$ $13 \cdot 10^{-3} \cdot I + 0.1 \text{ mA}$	coil with 5 turns coil with 10 turns coil with 50 turns coil with 250 turns
	> 100 V to 1100 V			
sources	1 μA to 220 μA		$50 \cdot 10^{-6} \cdot I + 9 \text{ nA}$ $50 \cdot 10^{-6} \cdot I + 80 \text{ nA}$ $60 \cdot 10^{-6} \cdot I + 0.5 \mu\text{A}$ $70 \cdot 10^{-6} \cdot I + 2 \mu\text{A}$ $0.24 \cdot 10^{-3} \cdot I + 10 \mu\text{A}$ $0.25 \cdot 10^{-3} \cdot I + 0.30 \text{ mA}$	I = measured value
	> 0.22 mA to 2.2 mA			
sources	> 2.2 mA to 22 mA			
	> 22 mA to 220 mA			
sources	> 0.22 A to 2.2 A			
	> 2.2 A to 10 A			
sources	> 50 mA to 50 A			
	> 50 mA to 250 A			
sources	> 5 A to 500 A			
	1 μA to 100 μA			
sources	> 1 mA to 10 mA			
	> 10 mA to 100 mA			
sources	> 0.1 A to 1 A			
	> 1 A to 10 A			
DC resistance measurement instruments	1 Ω		$90 \cdot 10^{-6} \cdot R$ $90 \cdot 10^{-6} \cdot R$ $60 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$ $0.1 \cdot 10^{-3} \cdot R$ $0.1 \cdot 10^{-3} \cdot R$ $20 \cdot 10^{-6} \cdot R$ $15 \cdot 10^{-6} \cdot R$ $75 \cdot 10^{-6} \cdot R$	R = measured value
	1.9 Ω			
	10 Ω			
	19 Ω			
	100 Ω			
	190 Ω			
	1.9 k Ω			
	10 k Ω			
	19 k Ω			
	100 k Ω			
	190 k Ω			
	1 M Ω			
	1.9 M Ω			
	10 M Ω			
	19 M Ω			
	100 M Ω			

¹⁾ The expanded uncertainties according to EA-4/02 M:2013 are part of CMC and are the best measurement uncertainties within accreditation. They have a coverage probability of approximately 95 % and have a coverage factor of $k = 2$ unless stated otherwise. Uncertainties without unit are relative uncertainties referring to the measurement value unless stated otherwise.

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹⁾	Remarks
DC resistance resistors	1 Ω to 10 Ω > 10 Ω to 100 Ω > 100 Ω to 1 MΩ > 1 MΩ to 10 MΩ > 10 MΩ to 100 MΩ		$20 \cdot 10^{-6} \cdot R$ $15 \cdot 10^{-6} \cdot R$ $25 \cdot 10^{-6} \cdot R$ $40 \cdot 10^{-6} \cdot R$ $0.1 \cdot 10^{-3} \cdot R$	R = measured value
Frequency sources and measurement instruments	1 MHz to 10 MHz 0.1 Hz to 20 GHz		$1 \cdot 10^{-11} \cdot f$ $1 \cdot 10^{-8} \cdot f + U_{Tf}$	1 MHz step width U_{Tf} = trigger uncertainty
Rise time sources	14 ps to 25 ns	50 mV to 50 V	$3 \cdot 10^{-2} \cdot t_R + 4$ ps	Periodic signals and impulse amplitudes
measurement instruments	18 ps to 1 ns 500 ps to 3 ns 1.5 ns to 25 ns	10 mV to 250 mV 0.25 V to 3 V 25 V and 50 V	$3 \cdot 10^{-2} \cdot t_R + 8$ ps $2 \cdot 10^{-2} \cdot t_R + 65$ ps $2 \cdot 10^{-2} \cdot t_R + 120$ ps	t_R = rise time
current probes	1.5 ns to 20 ns 100 ns to 300 ns	0.5 A and 1A 5A	$3 \cdot 10^{-2} \cdot t_R + 200$ ps $3 \cdot 10^{-2} \cdot t_R$	
Oscilloscopes with oscilloscope calibrator	0.0 V to 0.1 V > 0.0 V to 1 V > 0.1 V to 5.6 V > 5.6 V to 222.4 V	1 MΩ or 50 Ω Input impedance	15 μV $0.50 \cdot 10^{-3} \cdot U + 26$ μV $0.22 \cdot 10^{-3} \cdot U + 65$ μV $0.26 \cdot 10^{-3} \cdot U + 50$ μV	with Fluke 9500 U = measured value
DC voltage		1 MΩ Input impedance	$0.30 \cdot 10^{-3} \cdot U$	U = measured value
Flatness	4.4 mV to 5.6 V 4.4 mV to 5.6 V 4.4 mV to 3.4 V 4.4 mV to 3.4 V 4.4 mV to 2.2 V	10 MHz to 100 MHz > 100 MHz to 550 MHz > 550 MHz to 1.1 GHz > 1.1 GHz to 2.5 GHz > 2.5 GHz to 3.2 GHz	0.22 dB 0.29 dB 0.37 dB 0.48 dB 0.48 dB	Measurement quantity: ratio of rms-value at frequency of interest- and reference frequency f_{ref} : 50 kHz to 10 MHz Measurement range: peak-to-peak value of incident wave $ T_{DUT} \leq 0.23$ (50 Ω)
DC resistance	50 Ω 75 Ω 1 MΩ		$0.11 \cdot 10^{-2} \cdot R$ $0.13 \cdot 10^{-2} \cdot R$ $0.12 \cdot 10^{-2} \cdot R$	R = measured value
DC voltage sources	0 V to 5 V		$0.14 \cdot 10^{-3} \cdot U + 90$ μV	U = measured value
Frequency sources	12 kHz to 3.2 GHz		$0.27 \cdot 10^{-6}$	

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On-site Calibration

Calibration and Measurement Capabilities (CMC)

Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹⁾	Remarks
Rise time sources	40 ps to 25 ns	50 mV to 50 V	$4 \cdot 10^{-2} \cdot t_R + 4 \text{ ps}$	Periodic signals Impulse amplitudes
measurement instruments	40 ps to 1 ns 500 ps to 3 ns 1.5 ns to 25 ns	10 mV to 250 mV 0.25 V to 3 V 25 V and 50 V	$4 \cdot 10^{-2} \cdot t_R + 8 \text{ ps}$ $2 \cdot 10^{-2} \cdot t_R + 65 \text{ ps}$ $2 \cdot 10^{-2} \cdot t_R + 120 \text{ ps}$	$t_R = \text{rise time}$
current probes	1.5 ns to 20 ns 100 ns to 300 ns	0.5 A and 1A 5A	$3 \cdot 10^{-2} \cdot t_R + 200 \text{ ps}$ $3 \cdot 10^{-2} \cdot t_R$	
Oscilloscopes with oscilloscope calibrator DC voltage	0.0 V > 0.0 V to 0.1 V > 0.1 V to 1 V > 1 V to 5.6 V > 5.6 V to 222.4 V	1 MΩ or 50 Ω Input impedance 1 MΩ Input impedance	15 μV $0.50 \cdot 10^{-3} \cdot U + 26 \text{ μV}$ $0.22 \cdot 10^{-3} \cdot U + 65 \text{ μV}$ $0.26 \cdot 10^{-3} \cdot U + 50 \text{ μV}$ $0.30 \cdot 10^{-3} \cdot U$	$U = \text{measured value}$
Flatness	4.4 mV 4 to 5.6 V 4.4 mV to 5.6 V 4.4 mV to 3.4 V 4.4 mV to 3.4 V 4.4 mV to 2.2 V	10 MHz to 100 MHz > 100 MHz to 550 MHz > 550 MHz to 1.1 GHz > 1.1 GHz to 2.5 GHz > 2.5 GHz to 3.2 GHz	0.22 dB 0.29 dB 0.37 dB 0.48 dB 0.48 dB	Measurement quantity: ratio of rms-value at frequency of interest- and reference frequency f_{ref} : 50 kHz to 10 MHz Measurement range: peak- to-peak value of incident wave $ Γ_{DUT} \leq 0.23 (50 \Omega)$
Frequency sources	12 kHz to 3.2 GHz		$0.27 \cdot 10^{-6}$	

Abbreviations used:

EA-4/02 M: 2013 Evaluation of the Uncertainty of Measurement in Calibration, European co-operation for Accreditation

¹⁾ The expanded uncertainties according to EA-4/02 M:2013 are part of CMC and are the best measurement uncertainties within accreditation. They have a coverage probability of approximately 95 % and have a coverage factor of $k = 2$ unless stated otherwise. Uncertainties without unit are relative uncertainties referring to the measurement value unless stated otherwise.